

## TM2G0650170D

### 1700V N-Channel Silicon Carbide Power MOSFET

$V_{DS}$	=	1700 V
$R_{DS\ (on)}$	=	650 mΩ
$I_D$	=	9 A

### Features

- High blocking voltage
- Low on-resistance with high junction temperature
- High-speed switching with low capacitances
- Fast intrinsic diode with low reverse recovery (Qrr)
- RoHS compliant

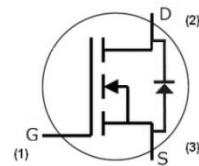
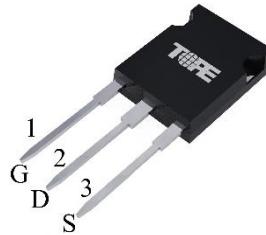
### Benefits

- Higher System Efficiency
- Reduce cooling requirements
- Increased power density
- Enabling higher frequency
- Minimize gate ringing
- Reduction of system complexity and cost

### Applications

- Switch Mode Power Supplies
- DC/DC converters
- Solar Inverters
- Battery Chargers
- Motor Drives

### Package



Part Number	Package	Marking
TM2G0650170D	TO-247-3	TM2G0650170D

### Maximum Ratings (T<sub>c</sub> = 25 °C unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions	Note
$V_{DSmax}$	Drain-Source Breakdown Voltage	1700	V	$V_{GS} = 0$ V, $I_D = 100$ μA	
$I_D$	Continuous Drain Current	9	A	$V_{GS} = 20$ V, $T_c = 25$ °C	Fig. 18
$I_{D(pulse)}$	Pulsed Drain Current	18	A	Pulse width $t_p$ limited by $T_{jmax}$	Fig. 21
$P_D$	Power Dissipation	85	W	$T_c = 25$ °C	Fig. 19
$V_{GS,op}$	Recommend Gate Source Voltage	-5/+20	V		
$V_{GSmax}$	Maximum Gate Source Voltage	-10/+25	V		
$T_j, T_{stg}$	Operating Junction and Storage Temperature Range	-55 to +175	°C		
$T_L$	Soldering Temperature	260	°C		

## Electrical Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions	Note		
Static									
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	1700	--	--	V	$V_{GS} = 0 \text{ V}, I_D = 100 \mu\text{A}$			
$I_{DSS}$	Zero Gate Voltage Drain Current	--	0.9	100	$\mu\text{A}$	$V_{DS} = 1700 \text{ V}, V_{GS} = 0 \text{ V}$			
$I_{GSS}$	Gate-Source Leakage	--	2	250	nA	$V_{GS} = 20 \text{ V}$			
$V_{GS(\text{th})}$	Gate-Source Threshold Voltage	1.8	--	4.0	V	$I_D = 0.5 \text{ mA}, V_{GS} = V_{DS}$	Fig. 11		
$R_{DS(\text{on})}$	Drain-Source On- Stage Resistance	--	550	1000	$\text{m}\Omega$	$V_{GS} = 20 \text{ V}, I_D = 2 \text{ A}$	Fig. 6		
		--	650		$\text{m}\Omega$	$V_{GS} = 18 \text{ V}, I_D = 2 \text{ A}$			
		--	780		$\text{m}\Omega$	$V_{GS} = 15 \text{ V}, I_D = 2 \text{ A}$			
Dynamic									
$C_{iss}$	Input Capacitance	--	183	--	pF	$V_{GS} = 0 \text{ V}, V_{DS} = 1000 \text{ V}$ $f = 1.0 \text{ MHz}, V_{AC} = 25 \text{ mV}$	Fig. 17		
$C_{oss}$	Output Capacitance	--	17.1	--					
$C_{rss}$	Reverse Transfer Capacitance	--	2.1	--					
$E_{oss}$	$C_{oss}$ Stored Energy	--	10.1	--	$\mu\text{J}$	$V_{DS} = 1200 \text{ V}$ $I_D = 2 \text{ A}$ $V_{GS} = -5/+20 \text{ V}$	Fig. 16		
$Q_g$	Total Gate Charge	--	13.2	--	nC				
$Q_{gs}$	Gate-Source Charge	--	5.0	--					
$Q_{gd}$	Gate-Drain Charge	--	4.5	--					
$E_{On}$	Turn-On Switching Energy		170		$\mu\text{J}$	$V_{DS} = 1000 \text{ V}, V_{GS} = -5/+20 \text{ V}$ $I_D = 2 \text{ A}, R_{G(\text{ext})} = 2.5 \Omega,$ $L = 70 \text{ mH}$	Fig. 22		
$E_{Off}$	Turn Off Switching Energy		68						
$t_{d(on)}$	Turn-on Delay Time	--	5	--	ns				
$t_r$	Turn-on Rise Time	--	17	--	$V_{DS} = 1000 \text{ V}$ $V_{GS} = -5/+20 \text{ V}$ $I_D = 2 \text{ A}, L = 70 \text{ mH}$ $R_{G(\text{ext})} = 2.5 \Omega$	Fig. 24			
$t_{d(off)}$	Turn-off Delay Time	--	13	--					
$t_f$	Turn-off Fall Time	--	55.6	--					
$R_{G(\text{int})}$	Internal Gate Resistance	--	25.2	--	$\Omega$	$f = 1.0 \text{ MHz}, V_{AC} = 25 \text{ mV}$			

## Body Diode Characteristics, at $T_J = 25^\circ\text{C}$ , unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions	Note
$I_S$	Continuous Diode Foward Current	--	--	4	A		
$V_{SD}$	Diode Foward Voltage	--	4.0	--	V	$V_{GS} = 0 \text{ V}, I_S = 1 \text{ A}$	Fig. 8, 9, 10
$t_{rr}$	Reverse Recovery Time	--	33	--	ns	$I_S = 2 \text{ A}, V_{DS} = 1200 \text{ V}$ $V_{GS} = -5 \text{ V}$ $dif/dt = 1200 \text{ A}/\mu\text{s}$	
$Q_{rr}$	Reverse Recovery Charge	--	32	--	nC		
$I_{rrm}$	Peak Reverse Recovery Current	--	3	--	A		

## Thermal Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Unit	Note
$R_{\theta JC}$	Thermal Resistance from Junction to Case	--	1.74	--	$^\circ\text{C}/\text{W}$	Fig. 20

## Typical Performance

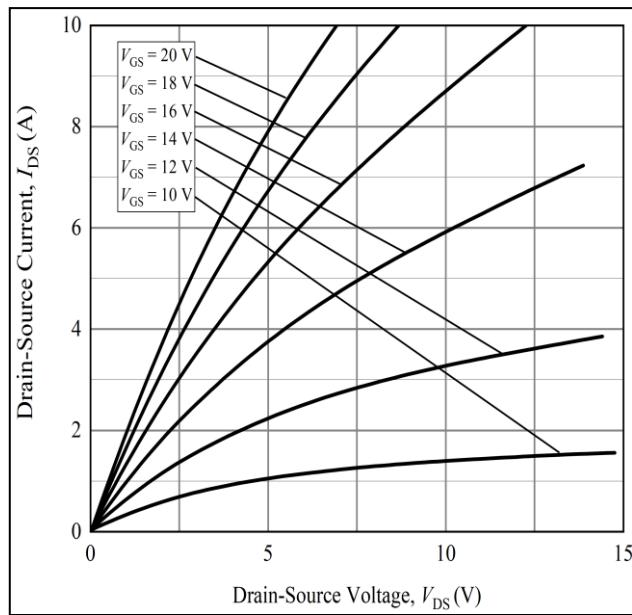


Figure 1: Typical Output Characteristics at  $T_J = -55\text{ }^{\circ}\text{C}$

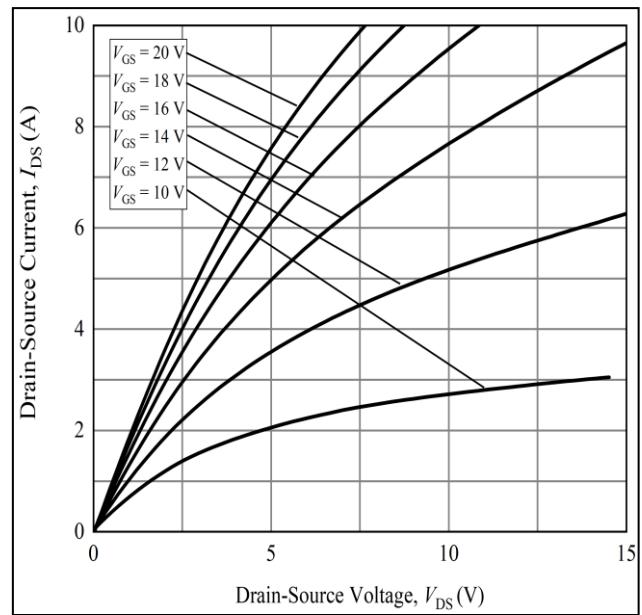


Figure 2: Typical Output Characteristics at  $T_J = 25\text{ }^{\circ}\text{C}$

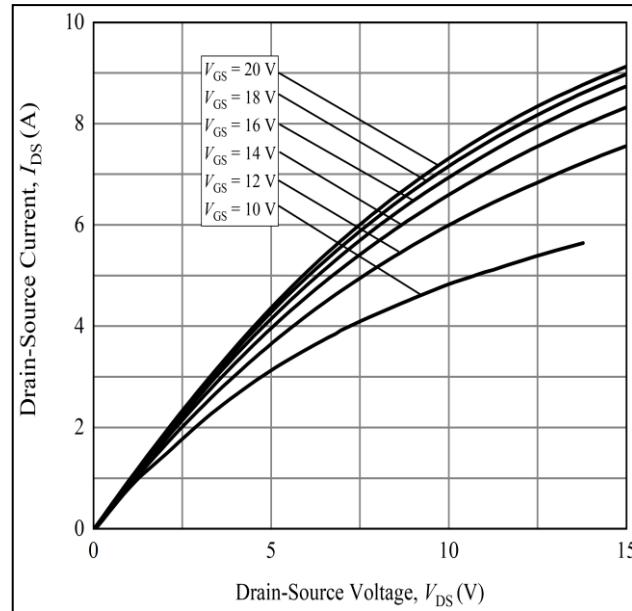


Figure 3: Typical Output Characteristics at  $T_J = 175\text{ }^{\circ}\text{C}$

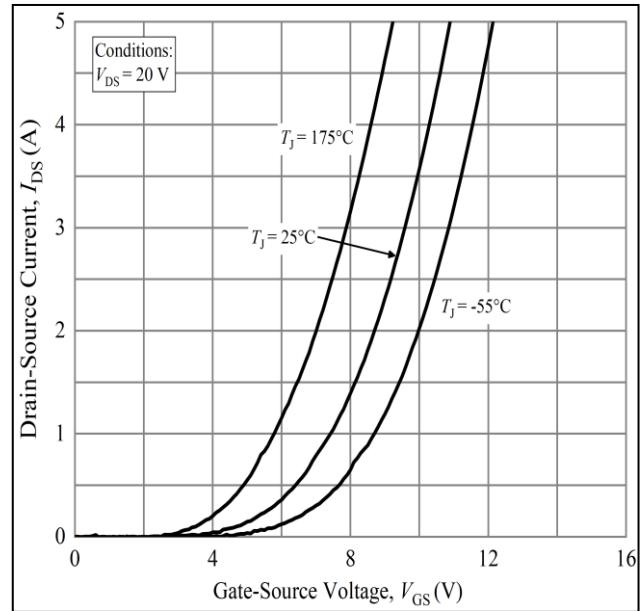
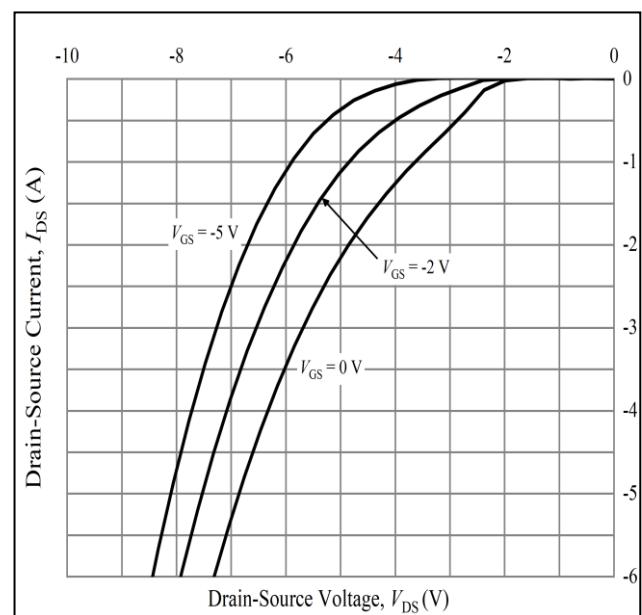
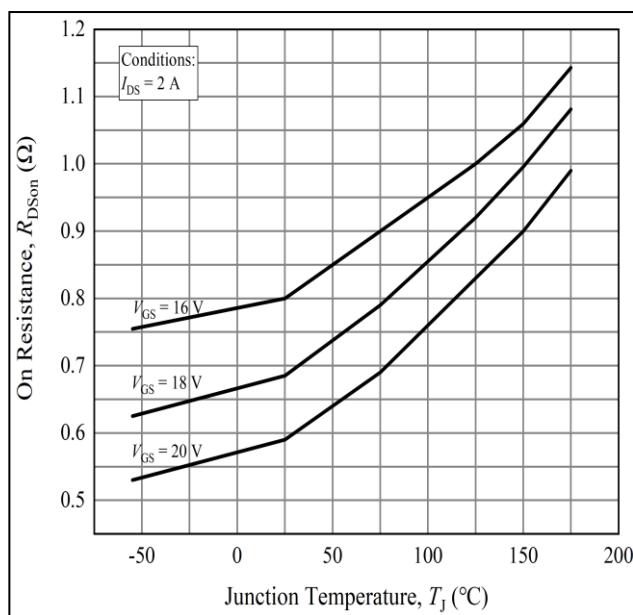
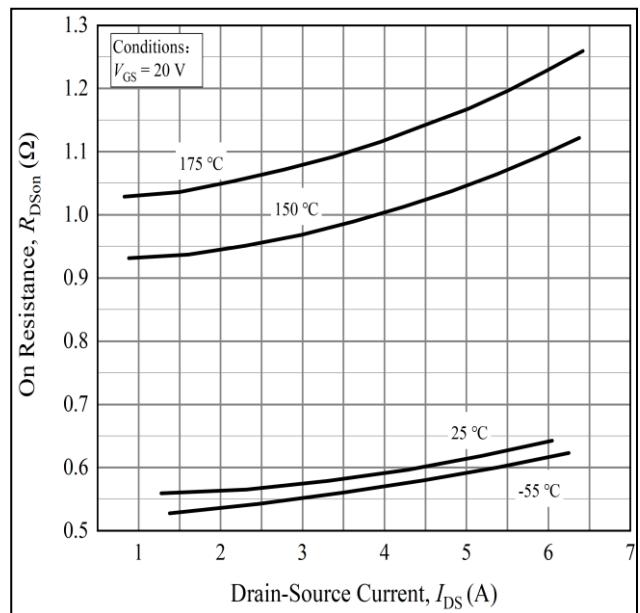
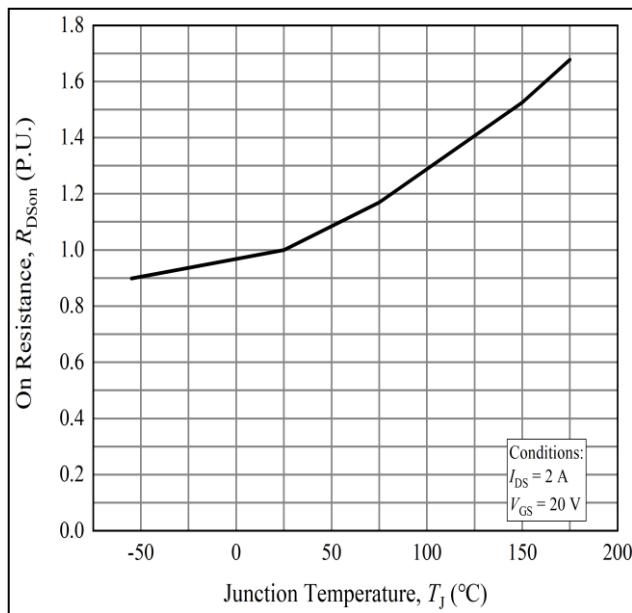


Figure 4: Typical Transfer Characteristics for Various Temperature

## Typical Performance



## Typical Performance

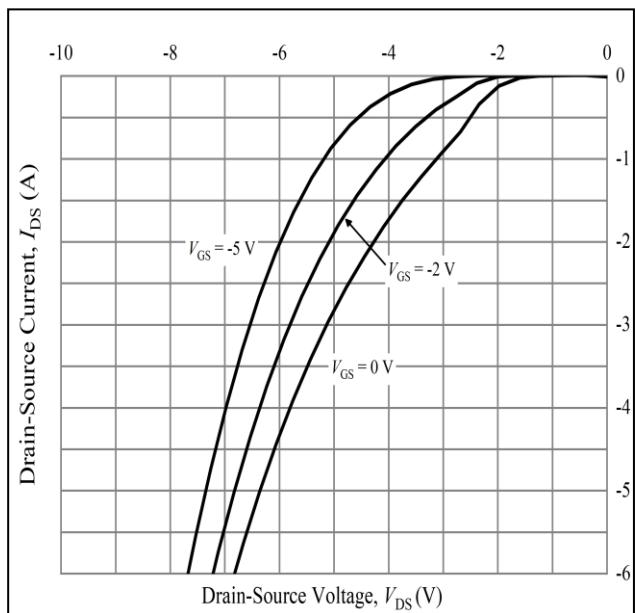


Figure 9: Typical Body Diode Characteristics at  
 $T_J = 25^\circ\text{C}$

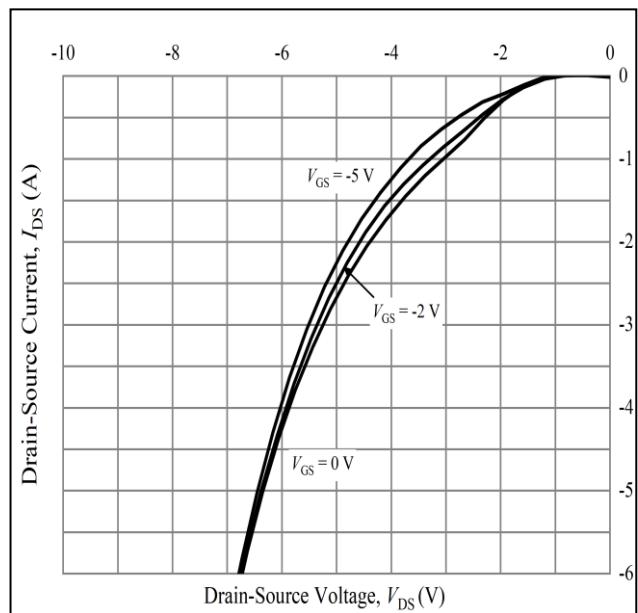


Figure 10: Typical Body Diode Characteristics at  
 $T_J = 175^\circ\text{C}$

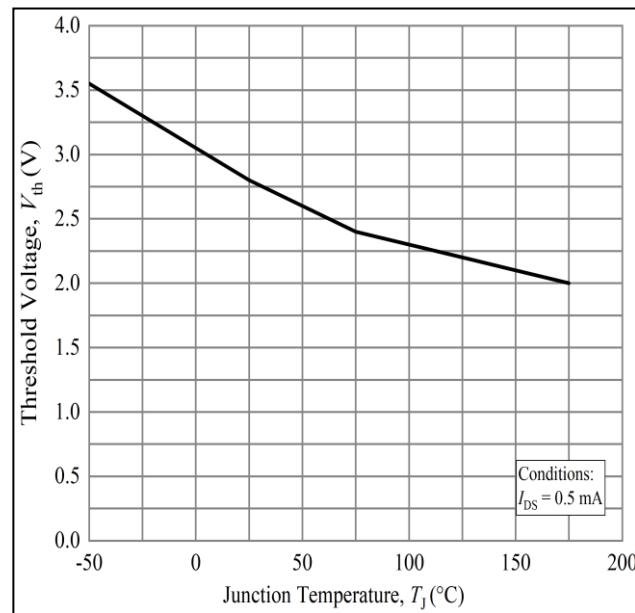


Figure 11: Typical Threshold Voltage vs. Temperature

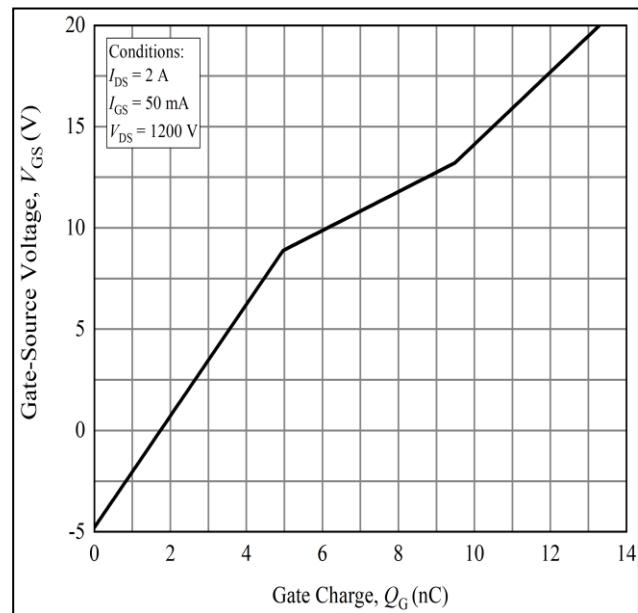


Figure 12: Typical Gate Charge Characteristics at  
 $T_J = 25^\circ\text{C}$

## Typical Performance

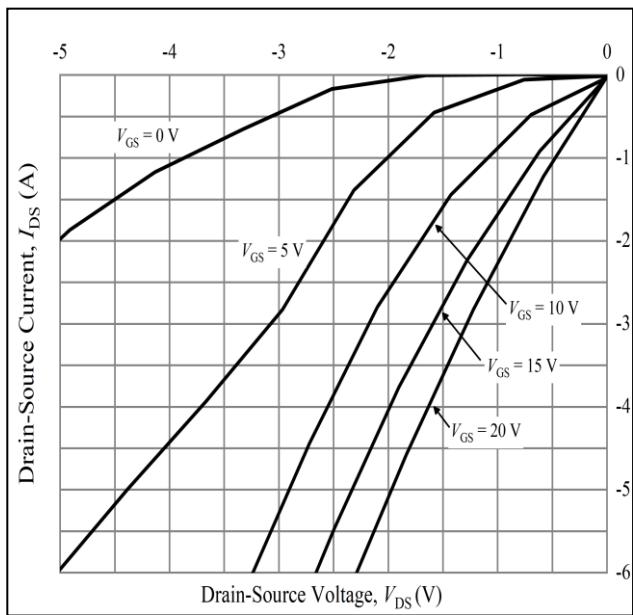


Figure 13: Typical 3rd Quadrant Characteristics  
 $T_J = -55 \text{ }^{\circ}\text{C}$

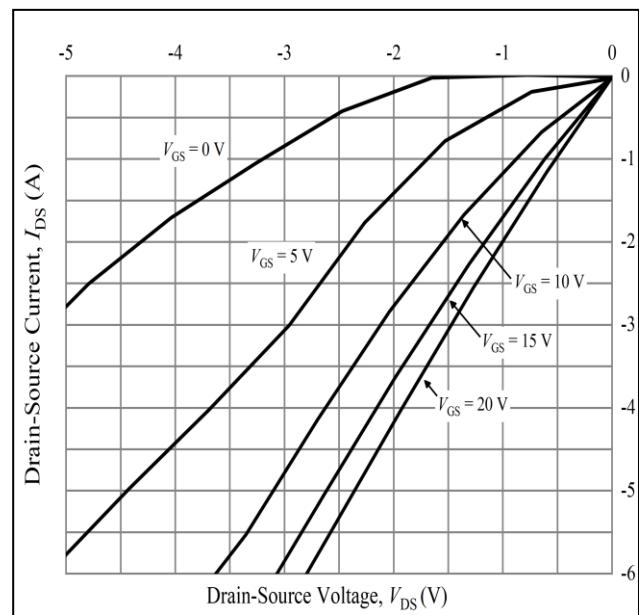


Figure 14: Typical 3rd Quadrant Characteristics at  
 $T_J = 25 \text{ }^{\circ}\text{C}$

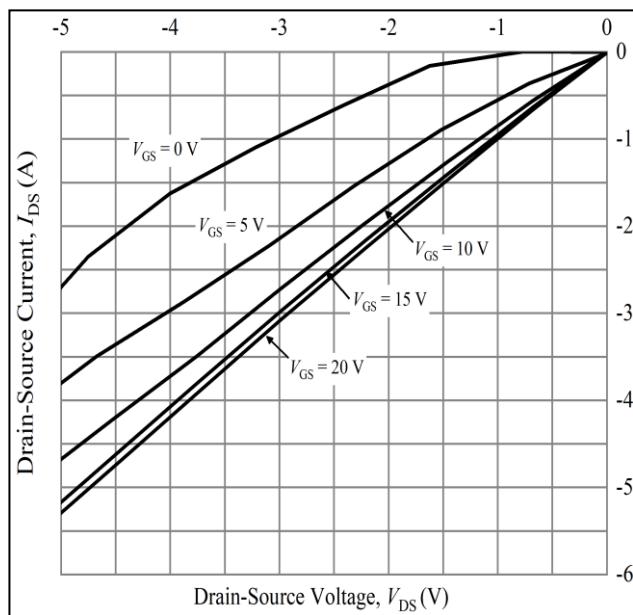


Figure 15: Typical 3rd Quadrant Characteristics at  
 $T_J = 175 \text{ }^{\circ}\text{C}$

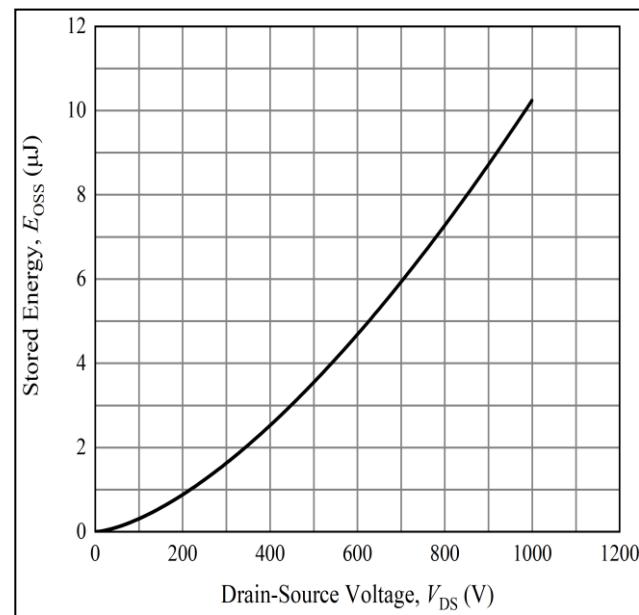


Figure 16: Typical Output Capacitor Stored Energy

## Typical Performance

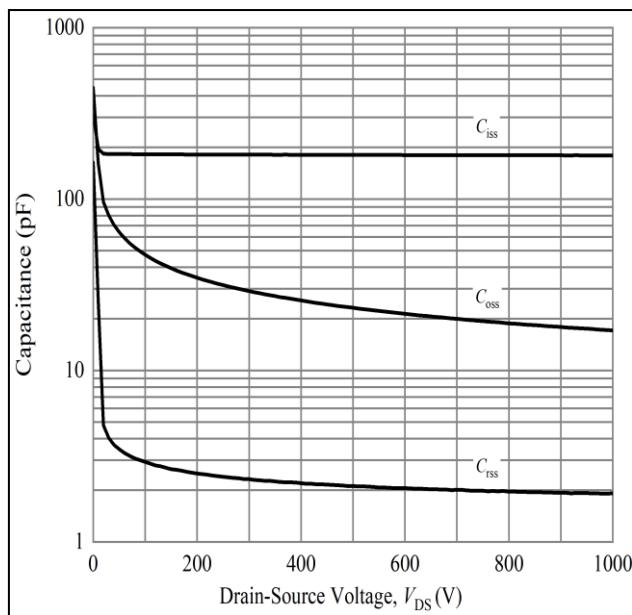


Figure 17: Typical Capacitances vs. Drain-Source Voltage

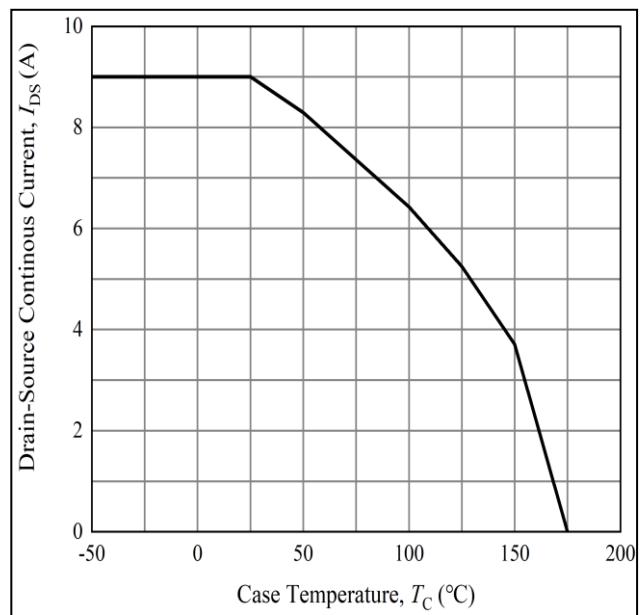


Figure 18: Continuous I<sub>DS</sub> Current Derating Curve

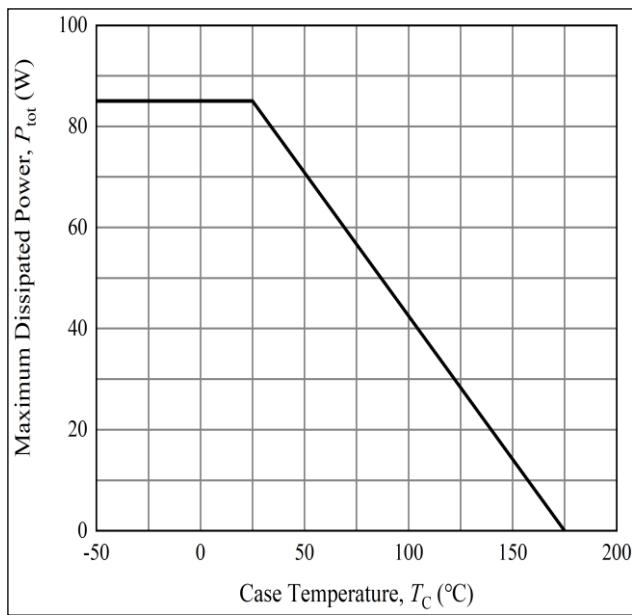


Figure 19: Power Dissipation Derating Curve

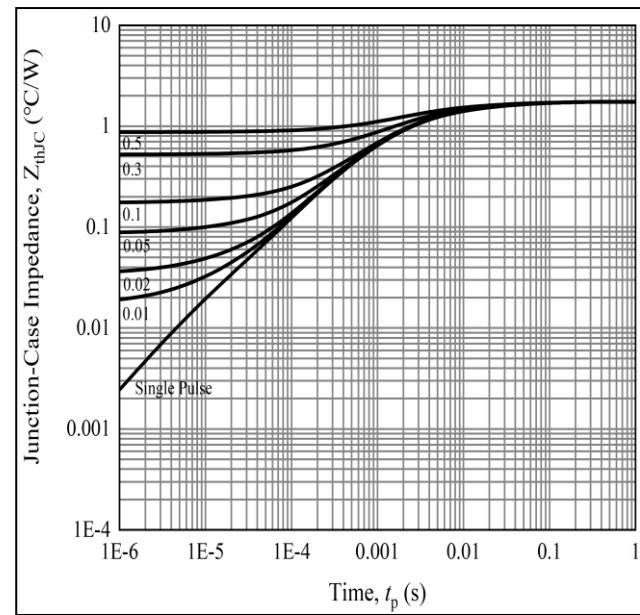


Figure 20: Typical Transient Thermal Impedance (Junction – Case) with Duty Cycle

## Typical Performance

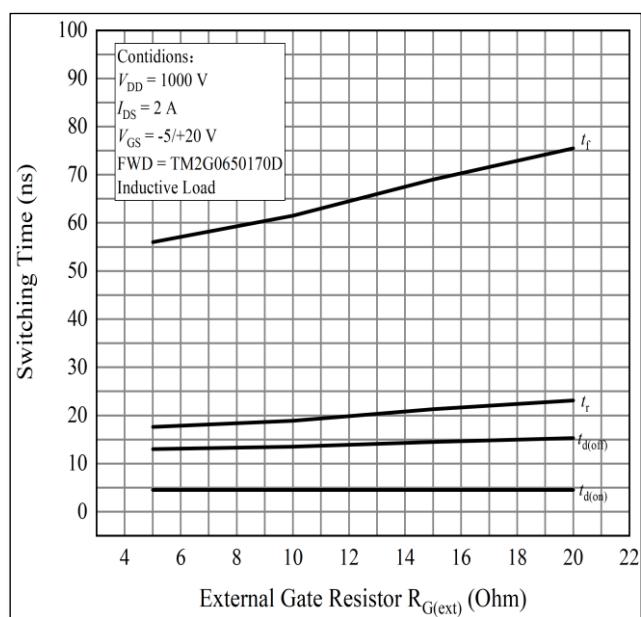
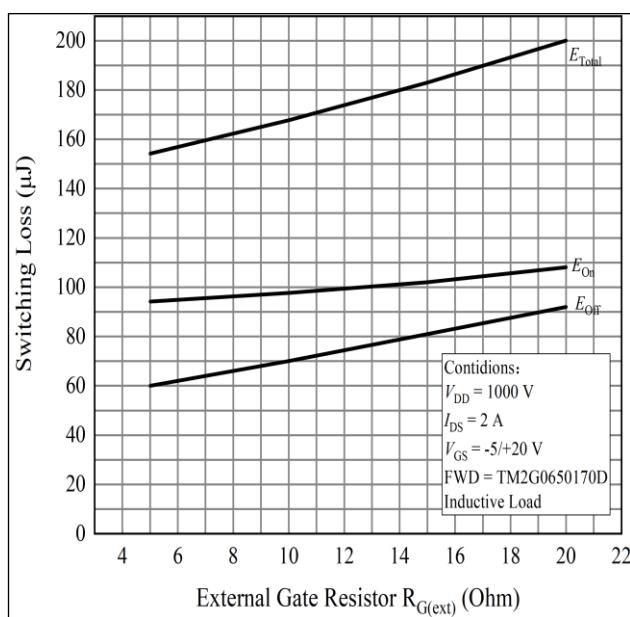
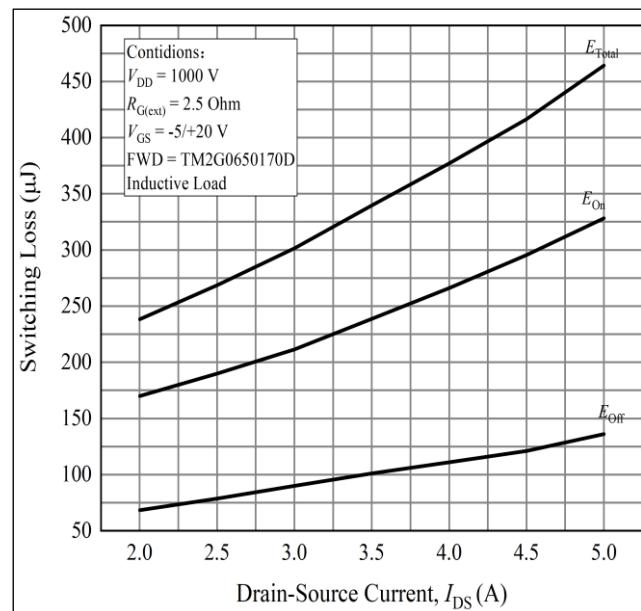
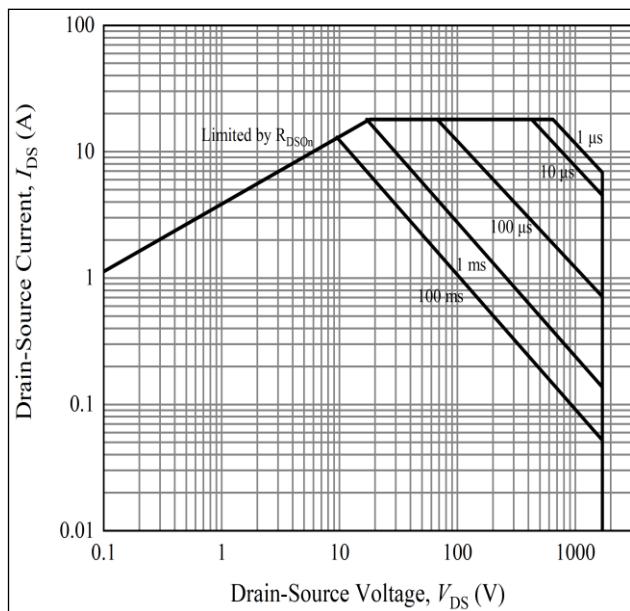


Figure 21: Safe Operate Area  
vs.  $R_{G(ext)}$

Figure 22: Clamped Inductive Switching Energy vs.  
Drain Current( $V_{DD} = 1000$  V)

## Typical Performance

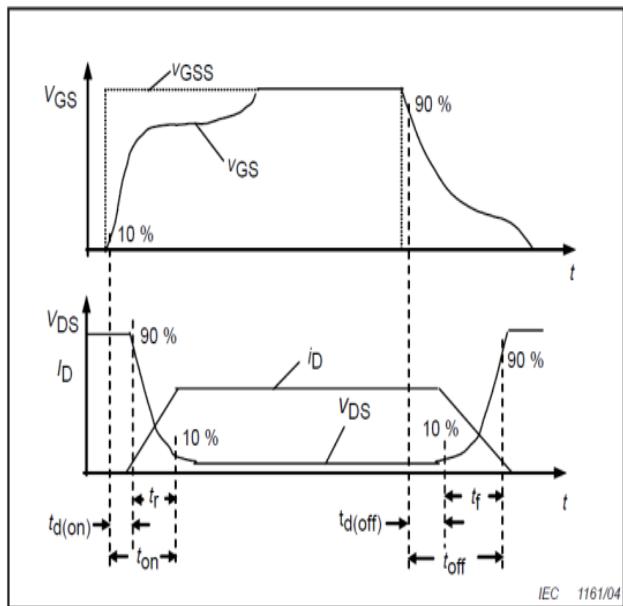


Figure 25: Resistive Switching Time Description

## Test Circuit Schematic

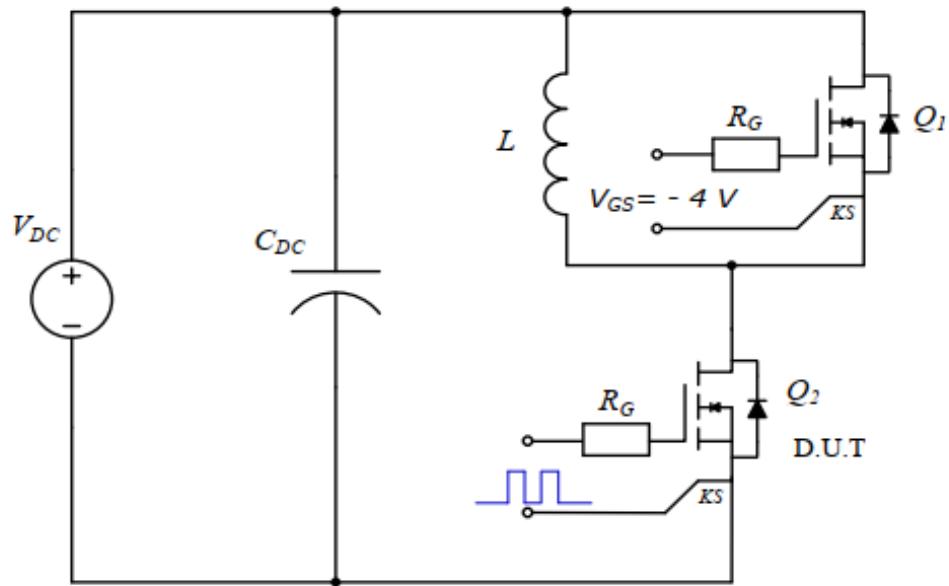
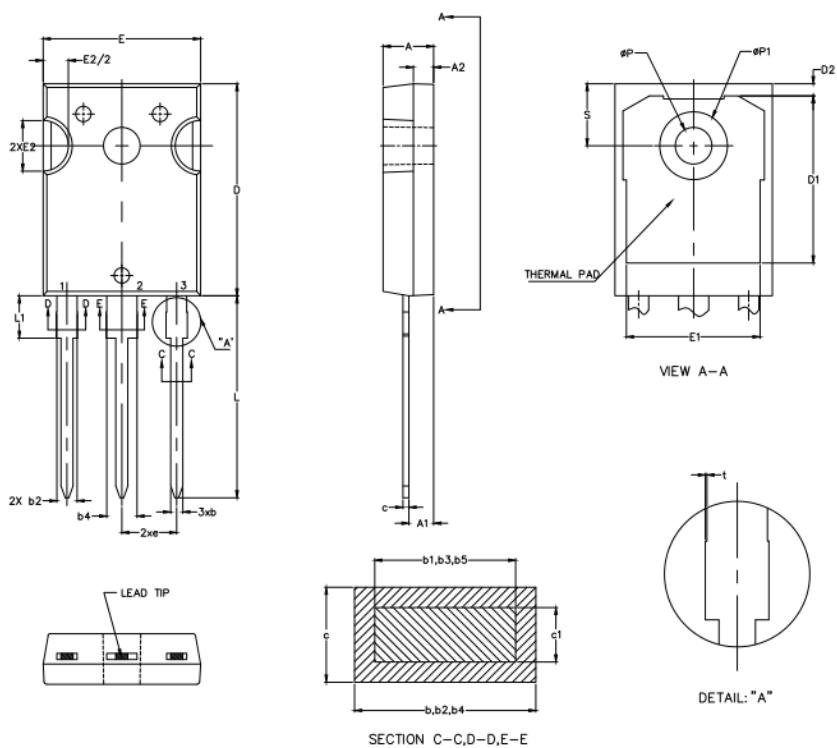


Figure 26: Clamped Inductive Switching Waveform Test Circuit

## Package Dimensions

Package: TO-247-3



S P E C I F T I O N S	DIMENSIONS			
	mm		inch	
	MIN.	MAX.	MIN.	MAX.
A	4.90	5.10	0.193	0.201
A1	2.31	2.51	0.091	0.099
A2	1.90	2.10	0.075	0.083
b	1.16	1.26	0.046	0.050
b1	1.15	1.22	0.045	0.048
b2	1.96	2.06	0.077	0.081
b3	1.95	2.02	0.077	0.080
b4	2.96	3.06	0.117	0.120
b5	2.95	3.02	0.116	0.119
c	0.59	0.66	0.023	0.026
c1	0.58	0.62	0.023	0.024
D	20.90	21.10	0.823	0.831
D1	16.25	16.85	0.640	0.663
D2	1.05	1.35	0.041	0.053
E	15.75	15.90	0.620	0.626
E1	13.26	—	0.552	—
E2	4.90	5.10	0.193	0.201
e	5.44BSC	—	0.214BSC	—
L	19.80	20.10	0.780	0.791
L1	—	4.30	—	0.169
φP	3.50	3.70	0.138	0.146
φP1	—	7.40	—	0.291
S	6.05	6.25	0.238	0.246
t	0.00	0.15	0.000	0.006

## Revision History

Document Version	Description of Changes

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